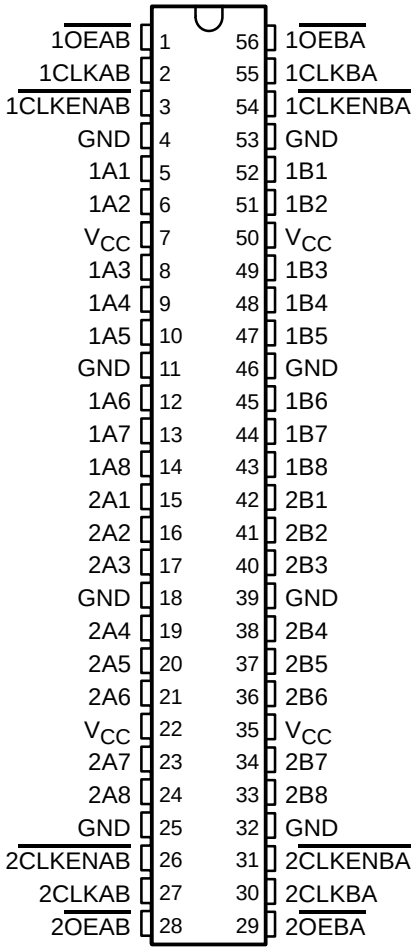
- **Member of the Texas Instruments *Widebus*™ Family**
- ***EPIC*™ (Enhanced-Performance Implanted CMOS) Submicron Process**
- **ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)**
- **Latch-Up Performance Exceeds 500 mA Per JEDEC Standard JESD-17**
- **Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors**
- **Package Options Include Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages**

**DGG OR DL PACKAGE**
**(TOP VIEW)**




## description

This 16-bit registered transceiver is designed for 2.3-V to 3.6-V $V_{CC}$ operation.

The SN74ALVCH16952 contains two sets of D-type flip-flops for temporary storage of data flowing in either direction. This device can be used as two 8-bit transceivers or one 16-bit transceiver. Data on the A or B bus is stored in the registers on the low-to-high transition of the clock (CLKAB or CLKBA) input provided that the clock-enable ($\overline{\text{CLKENAB}}$ or $\overline{\text{CLKENBA}}$) input is low. Taking the output-enable ($\overline{\text{OEAB}}$ or $\overline{\text{OEBA}}$) input low accesses the data on either port.

To ensure the high-impedance state during power up or power down, $\overline{\text{OE}}$ should be tied to $V_{CC}$ through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74ALVCH16952 is characterized for operation from –40°C to 85°C.

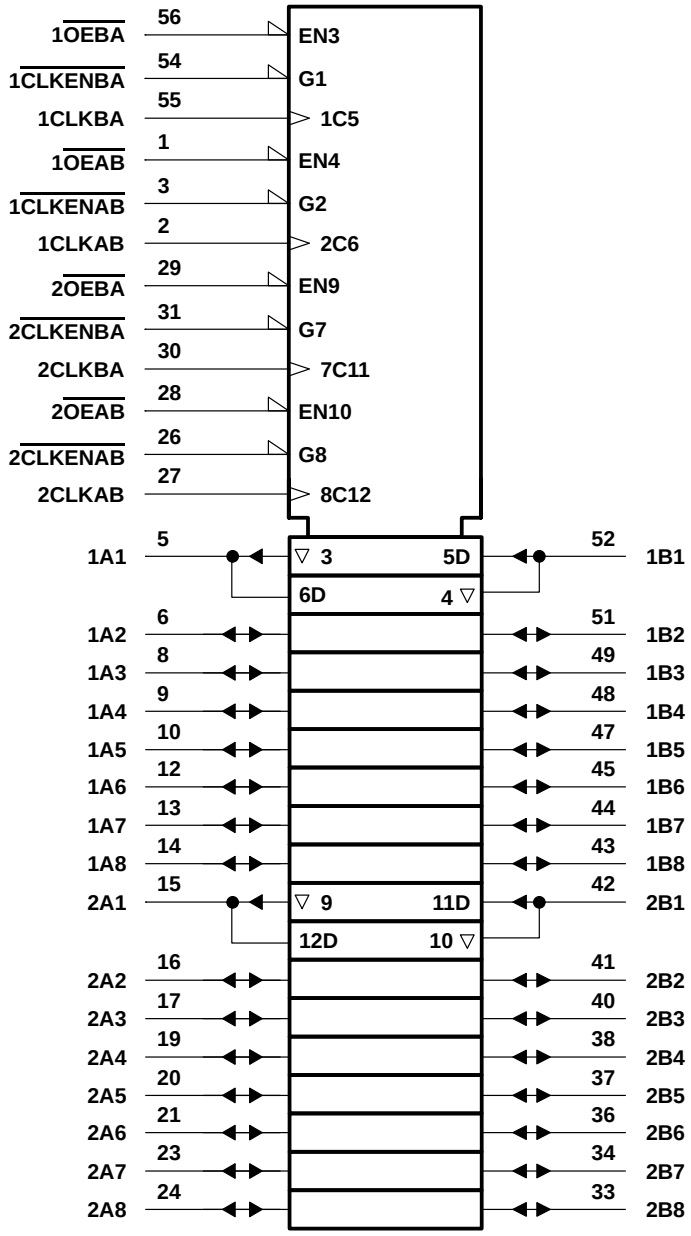
**FUNCTION TABLE†**

| INPUTS | | | | OUTPUT |
|---|---|---|---|---|
| $\overline{\text{CLKENAB}}$ | CLKAB | $\overline{\text{OEAB}}$ | A | B |
| H | X | L | X | $B_0$‡ |
| X | L | L | X | $B_0$‡ |
| L | ↑ | L | L | L |
| L | ↑ | L | H | H |
| X | X | H | X | Z |

† A-to-B data flow is shown; B-to-A data flow is similar, but uses $\overline{\text{CLKENBA}}$, CLKBA, and $\overline{\text{OEBA}}$.

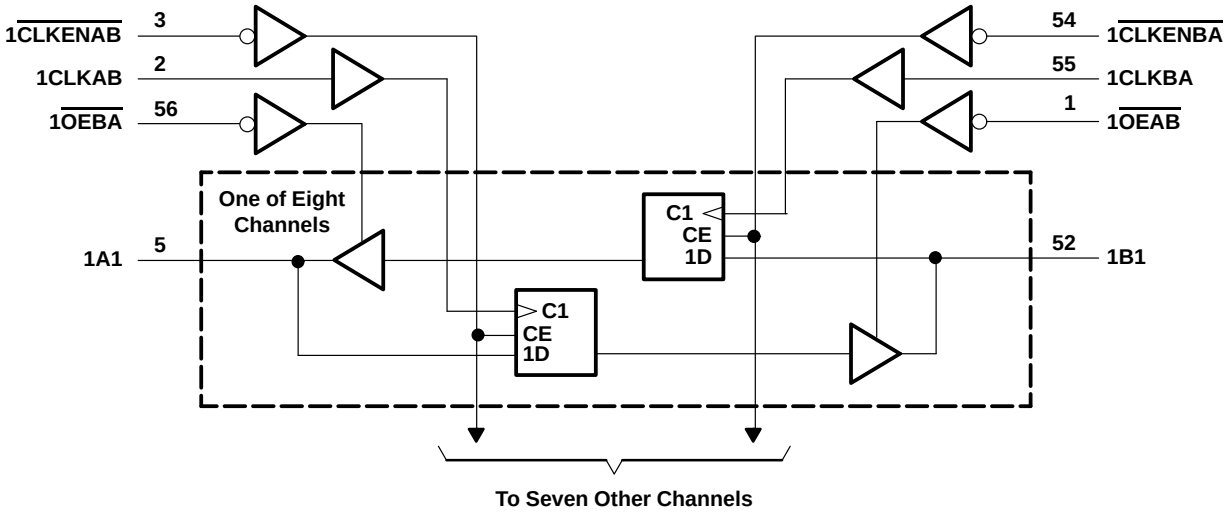
‡ Level of B before the indicated steady-state input conditions were established

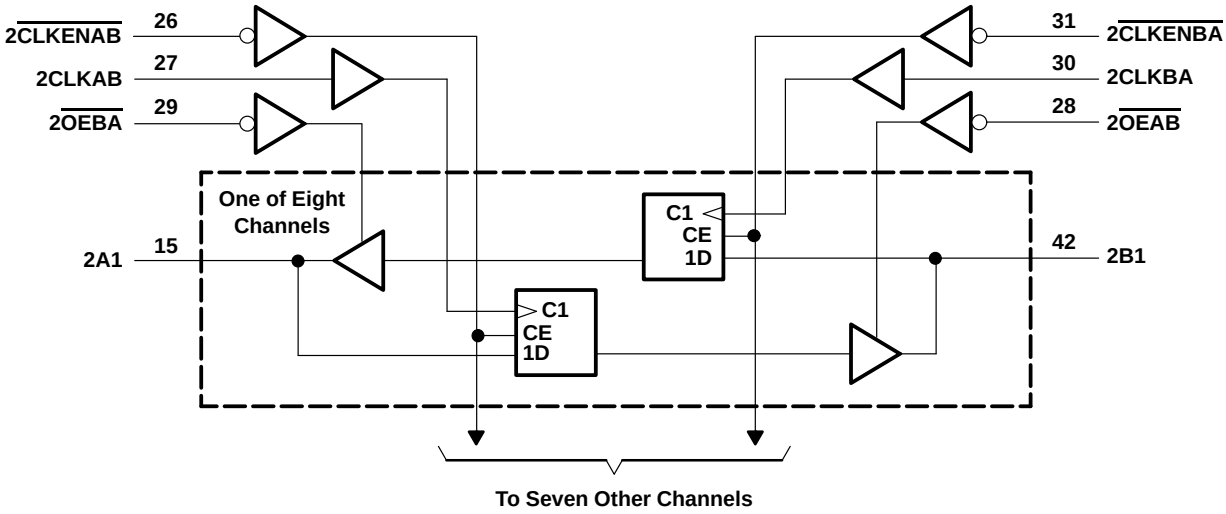
## logic symbol†




† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

## logic diagram (positive logic)



### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, $V_{CC}$ . . . . . –0.5 V to 4.6 V
Input voltage range, $V_I$: Except I/O ports (see Note 1) . . . . . –0.5 V to 4.6 V
I/O ports (see Notes 1 and 2) . . . . . –0.5 V to $V_{CC}$ + 0.5 V
Output voltage range, $V_O$ (see Notes 1 and 2) . . . . . –0.5 V to $V_{CC}$ + 0.5 V
Input clamp current, $I_{IK}$ ($V_I$ < 0) . . . . . –50 mA
Output clamp current, $I_{OK}$ ($V_O$ < 0 or $V_O$ > $V_{CC}$) . . . . . ±50 mA
Continuous output current, $I_O$ ($V_O$ = 0 to $V_{CC}$) . . . . . ±50 mA
Continuous current through each $V_{CC}$ or GND . . . . . ±100 mA
Package thermal impedance, $\theta_{JA}$ (see Note 3): DGG package . . . . . 81°C/W
DL package . . . . . 74°C/W
Storage temperature range, $T_{stg}$ . . . . . –65°C to 150°C

† Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with EIA/JEDEC Std JESD51.

### recommended operating conditions (see Note 4)

| | | | MIN | MAX | UNIT |
|---|---|---|---|---|---|
| $V_{CC}$ | Supply voltage | | 2.3 | 3.6 | V |
| $V_{IH}$ | High-level input voltage | $V_{CC}$ = 2.3 V to 2.7 V | 1.7 | | V |
| | | $V_{CC}$ = 2.7 V to 3.6 V | 2 | | |
| $V_{IL}$ | Low-level input voltage | $V_{CC}$ = 2.3 V to 2.7 V | | 0.7 | V |
| | | $V_{CC}$ = 2.7 V to 3.6 V | | 0.8 | |
| $V_I$ | Input voltage | | 0 | $V_{CC}$ | V |
| $V_O$ | Output voltage | | 0 | $V_{CC}$ | V |
| $I_{OH}$ | High-level output current | $V_{CC}$ = 2.3 V | | –12 | mA |
| | | $V_{CC}$ = 2.7 V | | –12 | |
| | | $V_{CC}$ = 3 V | | –24 | |
| $I_{OL}$ | Low-level output current | $V_{CC}$ = 2.3 V | | 12 | mA |
| | | $V_{CC}$ = 2.7 V | | 12 | |
| | | $V_{CC}$ = 3 V | | 24 | |
| $\Delta t/\Delta v$ | Input transition rise or fall rate | | 0 | 10 | ns/V |
| $T_A$ | Operating free-air temperature | | –40 | 85 | °C |

NOTE 4: Unused control inputs must be held high or low to prevent them from floating.

## electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

| PARAMETER | | TEST CONDITIONS | | $V_{CC}$ | MIN | TYP† | MAX | UNIT |
|---|---|---|---|---|---|---|---|---|
| $V_{OH}$ | | $I_{OH}$ = –100 μA | | 2.3 V to 3.6 V | $V_{CC}$–0.2 | | | V |
| | | $I_{OH}$ = –6 mA, | $V_{IH}$ = 1.7 V | 2.3 V | 2 | | | |
| | | $I_{OH}$ = –12 mA | $V_{IH}$ = 1.7 V | 2.3 V | 1.7 | | | |
| | | | $V_{IH}$ = 2 V | 2.7 V | 2.2 | | | |
| | | | | 3 V | 2.4 | | | |
| | | $I_{OH}$ = –24 mA, | $V_{IH}$ = 2 V | 3 V | 2 | | | |
| $V_{OL}$ | | $I_{OL}$ = 100 μA | | 2.3 V to 3.6 V | | | 0.2 | V |
| | | $I_{OL}$ = 6 mA, | $V_{IL}$ = 0.7 V | 2.3 V | | | 0.4 | |
| | | $I_{OL}$ = 12 mA | $V_{IL}$ = 0.7 V | 2.3 V | | | 0.7 | |
| | | | $V_{IL}$ = 0.8 V | 2.7 V | | | 0.4 | |
| | | $I_{OL}$ = 24 mA, | $V_{IL}$ = 0.8 V | 3 V | | | 0.55 | |
| $I_I$ | | $V_I$ = $V_{CC}$ or GND | | 3.6 V | | | ±5 | μA |
| $I_{I(hold)}$ | | $V_I$ = 0.7 V | | 2.3 V | 45 | | | μA |
| | | $V_I$ = 1.7 V | | 2.3 V | –45 | | | |
| | | $V_I$ = 0.8 V | | 3 V | 75 | | | |
| | | $V_I$ = 2 V | | 3 V | –75 | | | |
| | | $V_I$ = 0 to 3.6 V‡ | | 3.6 V | | | ±500 | |
| $I_{OZ}$§ | | $V_O$ = $V_{CC}$ or GND | | 3.6 V | | | ±10 | μA |
| $I_{CC}$ | | $V_I$ = $V_{CC}$ or GND, | $I_O$ = 0 | 3.6 V | | | 40 | μA |
| $\Delta I_{CC}$ | | One input at $V_{CC}$ – 0.6 V, | Other inputs at $V_{CC}$ or GND | 2.3 V to 3.6 V | | | 750 | μA |
| $C_i$ | Control inputs | $V_I$ = $V_{CC}$ or GND | | 3.3 V | | 3.5 | | pF |
| $C_{io}$ | A or B ports | $V_O$ = $V_{CC}$ or GND | | 3.3 V | | 8.5 | | pF |

† Typical values are measured at $V_{CC}$ = 3.3 V, $T_A$ = 25°C.
‡ This is the bus-hold maximum dynamic current required to switch the input from one state to another.
§ For I/O ports, the parameter $I_{OZ}$ includes the input leakage current.

## timing requirements over recommended operating free-air temperature range (unless otherwise noted)

| | | | $V_{CC}$ = 2.5 V ± 0.2 V | | $V_{CC}$ = 2.7 V | | $V_{CC}$ = 3.3 V ± 0.3 V | | UNIT |
|---|---|---|---|---|---|---|---|---|---|
| | | | MIN | MAX | MIN | MAX | MIN | MAX | |
| $f_{clock}$ | Clock frequency | | 0 | 150 | 0 | 150 | 0 | 150 | MHz |
| $t_w$ | Pulse duration | $\overline{\text{CLKEN}}$ high | 3.3 | | 3.3 | | 3.3 | | ns |
| | | CLK high or low | 3.3 | | 3.3 | | 3.3 | | |
| $t_{su}$ | Setup time | Data before CLK | 1.7 | | 1.9 | | 1.5 | | ns |
| | | $\overline{\text{CLKEN}}$ before CLK | 1.2 | | 1 | | 1 | | |
| $t_h$ | Hold time | Data after CLK | 0.6 | | 0.6 | | 0.8 | | ns |
| | | $\overline{\text{CLKEN}}$ after CLK | 1.1 | | 0.9 | | 1.1 | | |

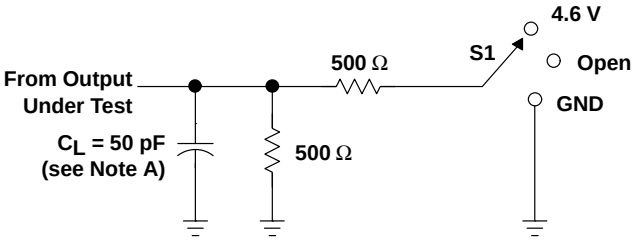
**switching characteristics over recommended ranges of supply voltage and operating free-air temperature range, $C_L$ = 50 pF (unless otherwise noted) (see Figures 1 and 2)**

| PARAMETER | FROM (INPUT) | TO (OUTPUT) | $V_{CC}$ = 2.5 V ± 0.2 V | | $V_{CC}$ = 2.7 V | | $V_{CC}$ = 3.3 V ± 0.3 V | | UNIT |
|---|---|---|---|---|---|---|---|---|---|
| | | | MIN | MAX | MIN | MAX | MIN | MAX | |
| $f_{max}$ | | | 150 | | 150 | | 150 | | MHz |
| $t_{pd}$ | CLK | A or B | 1 | 5.5 | | 4.6 | 1 | 3.9 | ns |
| $t_{en}$ | $\overline{OEBA}$ or $\overline{OEAB}$ | A or B | 1 | 5.9 | | 5.3 | 1 | 4.4 | ns |
| $t_{dis}$ | $\overline{OEBA}$ or $\overline{OEAB}$ | A or B | 1.3 | 5.5 | | 4.4 | 1.1 | 4 | ns |

**operating characteristics, $T_A$ = 25°C**

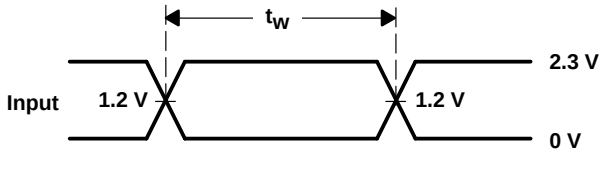
| PARAMETER | | | TEST CONDITIONS | $V_{CC}$ = 2.5 V ± 0.2 V | $V_{CC}$ = 3.3 V ± 0.3 V | UNIT |
|---|---|---|---|---|---|---|
| | | | | TYP | TYP | |
| $C_{pd}$ | Power dissipation capacitance | Outputs enabled | $C_L$ = 0, f = 10 MHz | 53 | 71 | pF |
| | | Outputs disabled | | 34 | 40 | |

## PARAMETER MEASUREMENT INFORMATION
## $V_{CC}$ = 2.5 V ± 0.2 V

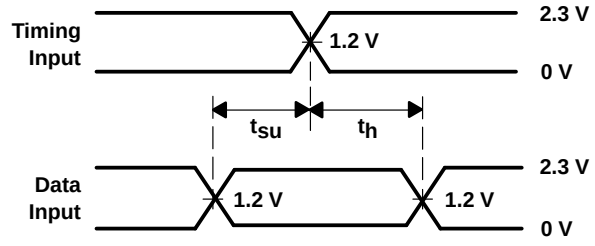



| TEST | S1 |
|---|---|
| $t_{pd}$ | Open |
| $t_{PLZ}/t_{PZL}$ | 4.6 V |
| $t_{PHZ}/t_{PZH}$ | GND |

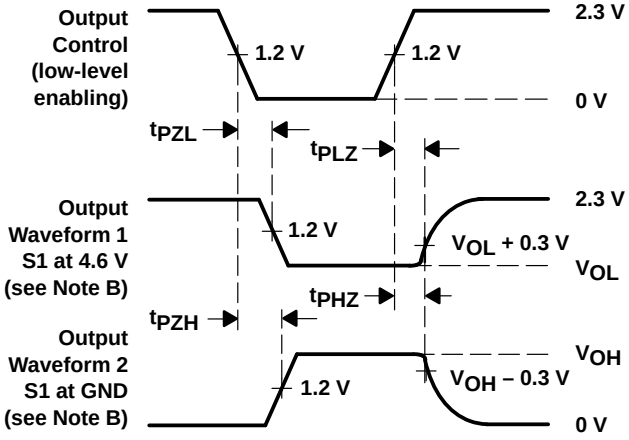
LOAD CIRCUIT



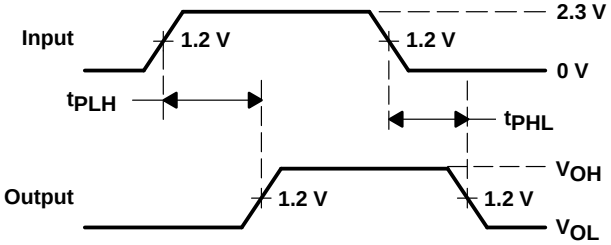

VOLTAGE WAVEFORMS
PULSE DURATION




VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES




VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES

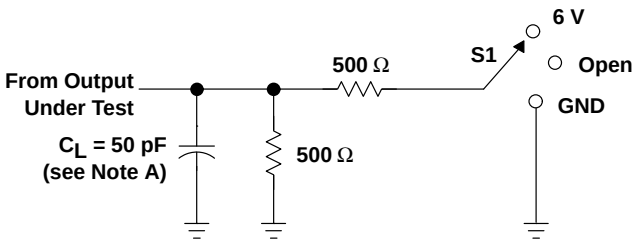



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES

NOTES: A. $C_L$ includes probe and jig capacitance.
B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
C. All input pulses are supplied by generators having the following characteristics: PRR ≤ 10 MHz, $Z_O$ = 50 Ω, $t_r$ ≤ 2.5 ns, $t_f$ ≤ 2.5 ns.
D. The outputs are measured one at a time with one transition per measurement.
E. $t_{PLZ}$ and $t_{PHZ}$ are the same as $t_{dis}$.
F. $t_{PZL}$ and $t_{PZH}$ are the same as $t_{en}$.
G. $t_{PHL}$ and $t_{PLH}$ are the same as $t_{pd}$.

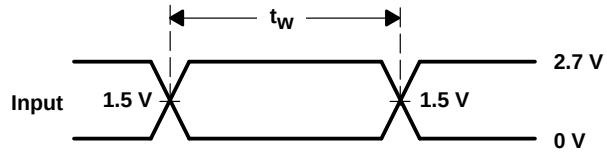
**Figure 1. Load Circuit and Voltage Waveforms**

## PARAMETER MEASUREMENT INFORMATION
## $V_{CC}$ = 2.7 V AND 3.3 V ± 0.3 V

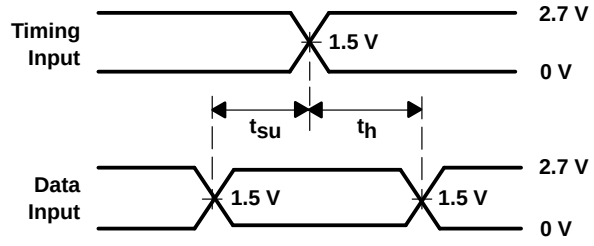



| TEST | S1 |
|---|---|
| $t_{pd}$ | Open |
| $t_{PLZ}/t_{PZL}$ | 6 V |
| $t_{PHZ}/t_{PZH}$ | GND |

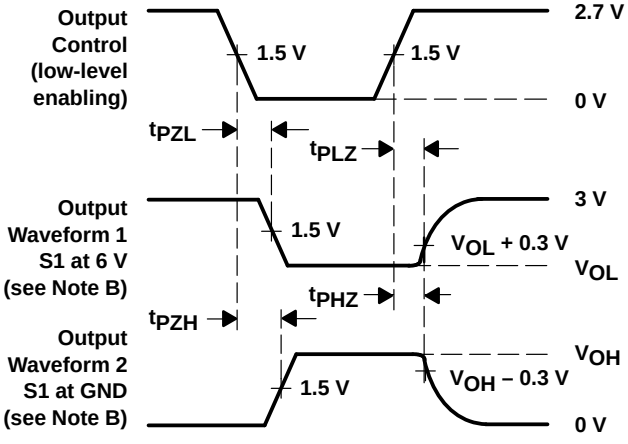
LOAD CIRCUIT



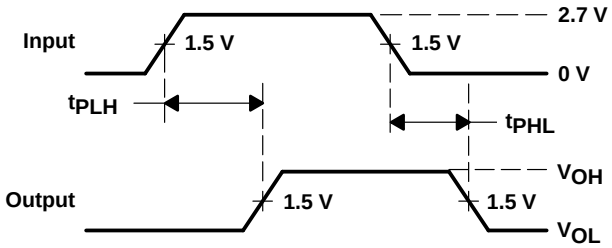

VOLTAGE WAVEFORMS
PULSE DURATION




VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES




VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES




VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES

NOTES: A. $C_L$ includes probe and jig capacitance.
B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
C. All input pulses are supplied by generators having the following characteristics: PRR ≤ 10 MHz, $Z_O$ = 50 Ω, $t_r$ ≤ 2.5 ns, $t_f$ ≤ 2.5 ns.
D. The outputs are measured one at a time with one transition per measurement.
E. $t_{PLZ}$ and $t_{PHZ}$ are the same as $t_{dis}$.
F. $t_{PZL}$ and $t_{PZH}$ are the same as $t_{en}$.
G. $t_{PHL}$ and $t_{PLH}$ are the same as $t_{pd}$.

**Figure 2. Load Circuit and Voltage Waveforms**

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